

Development of Photon noise limited Kinetic Inductance Detector Array

Jiansong Gao NIST

EAO meeting, Nanjing, May 21, 2019



Quantum Sensors Group, NIST Boulder



Group Leader: Joel Ullom

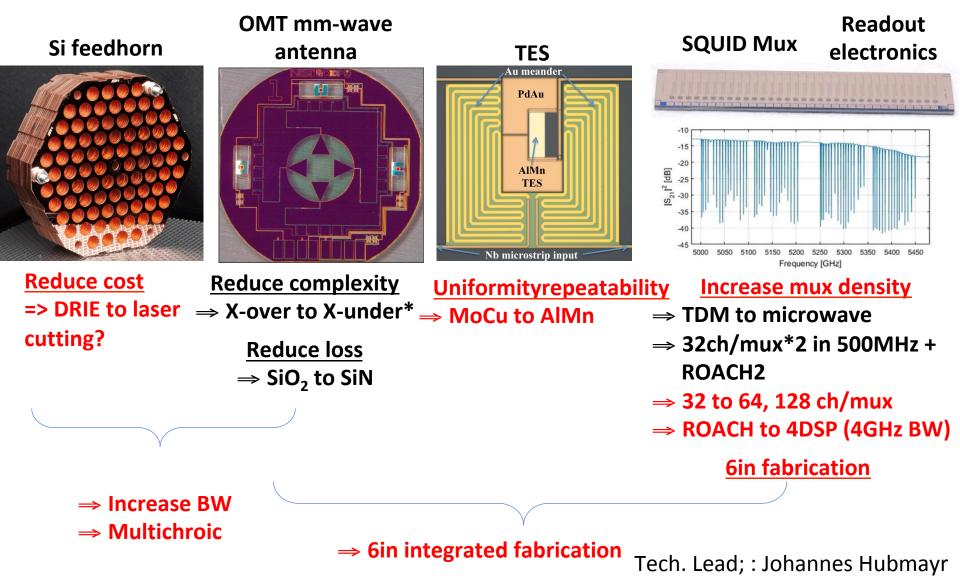
- Long-wavelength Project (TES and MKID): Johannes Hubmayr (lead), Jay Austermann, Jim Beall, Dan Becker, Brad Dober, Shannon Duff, Jiansong Gao, Gene Hilton (fab lead), Jeff Van Lanen, Mike Link, Tammy Lucas, Mike Vissers, Sam Walker

- Calorimeter project (so far only TES...)

TES bolometer Development at NIST



- Wavelength range: CMB (30GHz to 300GHz)
- Basic approcach: Feedhorn-OMT coupled TES + microwave SQUID Mux
- Ongoing projects: AdvancedACT, SPIDER, Simons array, ALI-CPT



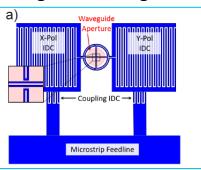
MKID Development at NIST



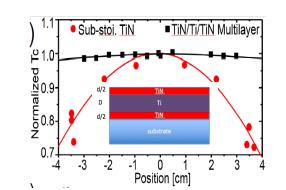
- Wavelength range: 150 GHz to 1.2THz; Ongoing projects: BLAST-TNG, TolTEC
- Basic MKID architecture: Feedhorn-coupled MKID polarimeters. Tech. Lead: Jiansong Gao
- Focus: Sensitivity, optical coupling, large array fabrication

Solved/accomplished during the project development of BLAST-TNG

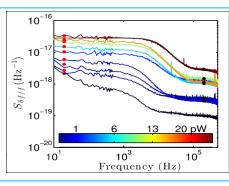
TiN absorber coupled dualpolarization sensitive noncrossing MKID design



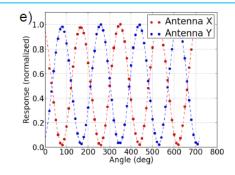
 Uniform and versatile TiN/Ti/ TiN tri-layer and multi-layer (Tc, R, t tunable)



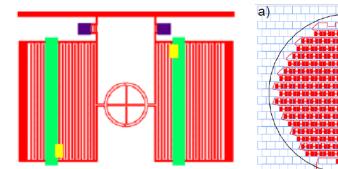
Photon-noise limited sensitivity at >3Hz from 250 um to 1mm

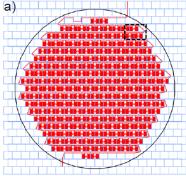


cross-pol & inter-pixel crosstalk <2%, optical efficiency ~ 60%

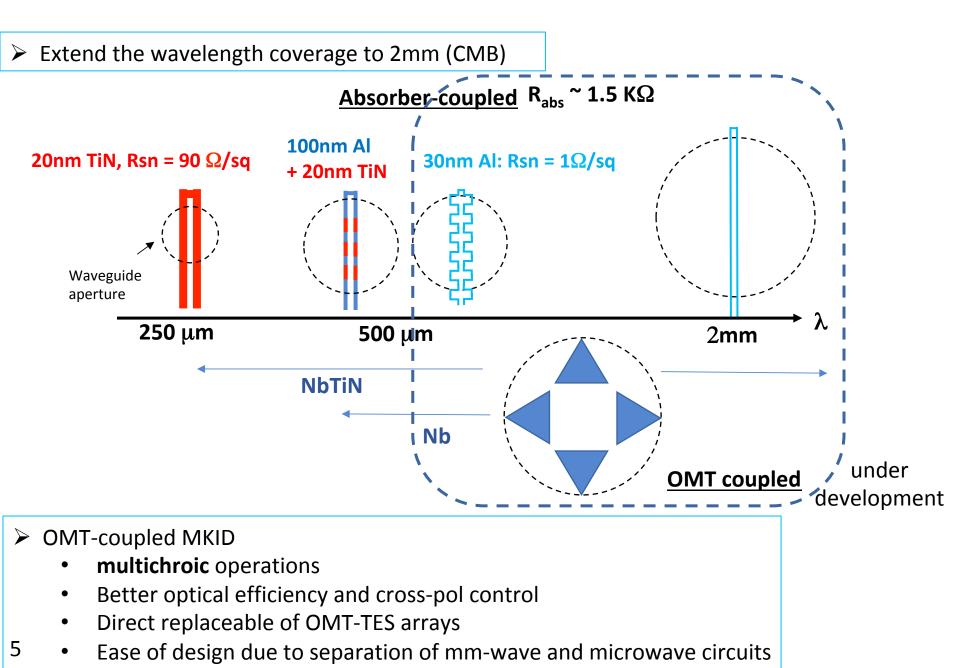


Scalable and flexible "tile-and trim" fabrication process

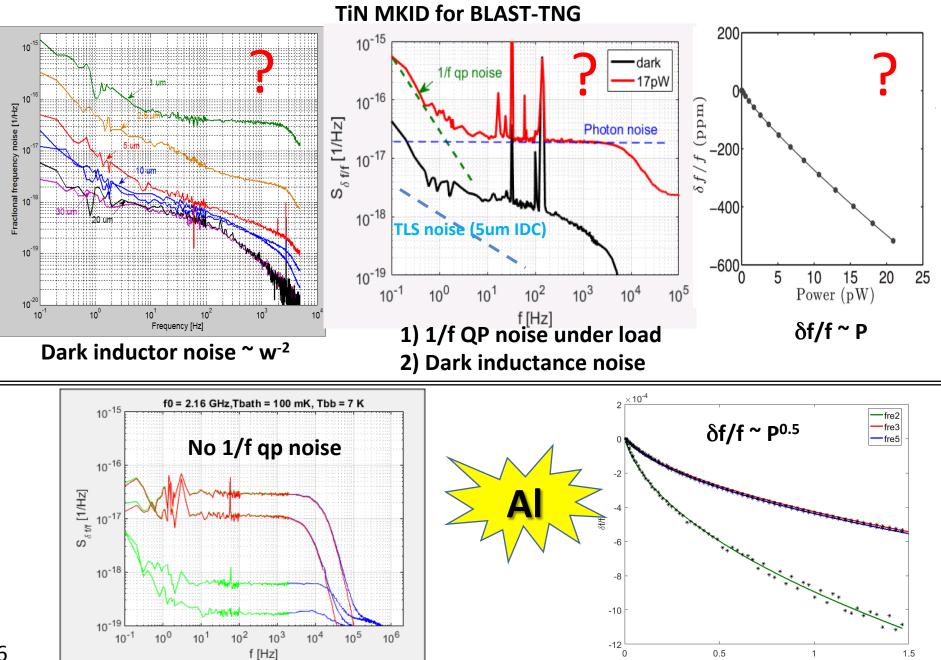




Not solved and direction of future development NIS



Extend the photon-noise limited performance down to 0.1 Hz

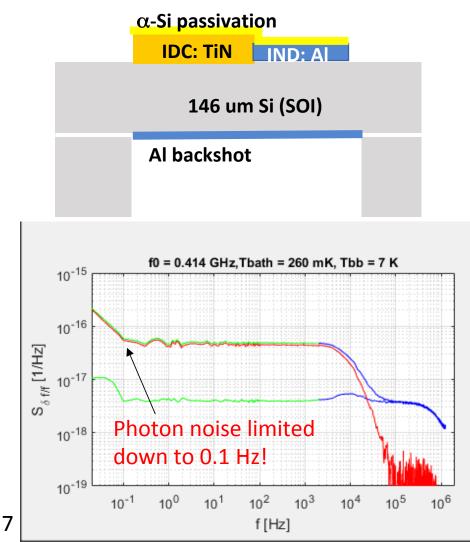


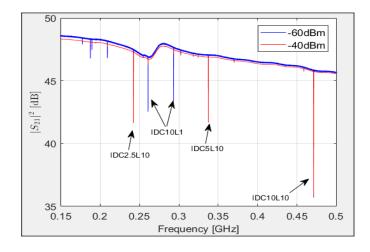
<u>×</u>10⁻¹¹

PBB [W]

New solution: TiN/Al hybrid MKID

- > Why hybrid? (1 yr of work to come to these conclusions)
 - TLS noise from Al IDC is 10 times higher than made from TiN
 - Al devices turn to degrade over time likely due to oxidation
 - Stoichiometric TiN (Tc ~4.5K) blocks Al (Tc~1.4 K) QPs from diffusion into IDC

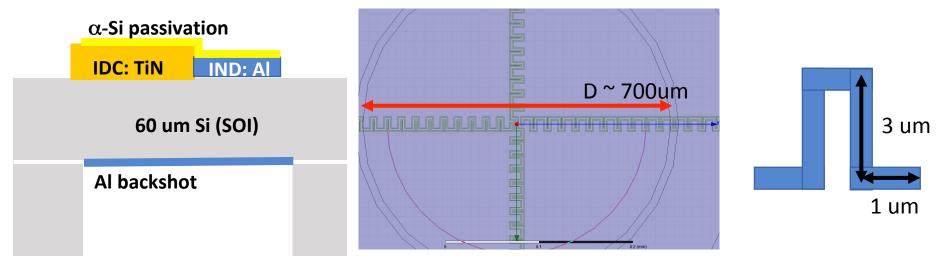




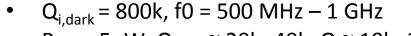
NEW

- IDC: thick TiN, Tc ~ 4.5K, w = g = 5, 10um
- Ind: 30nm sputtered Al, Tc ~ 1.4K
- Ind: w=1um, I = 2000um (*2), Rn =1 Ω /sq
- Tbath = 250mK (reduce TLS)
- Q_{i,dark} = 800 k, f0 = 200 500 MHz
- Q_{i,opt} ~ 20k -40k

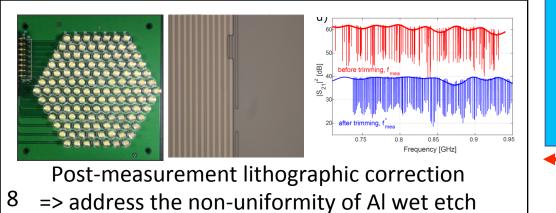
TiN/Al hybrid MKID for 850um band design concept NST

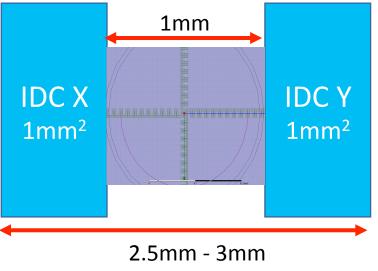


- IDC: thick TiN, Tc ~ 4.5K, w = g = 2.5 or 5um, area 1mm*1mm
- Ind: 30nm sputtered Al, Tc ~ 1.4K
- Ind: w=1um, I = 2800um (*2) meandered, $R_{abs} \sim 1.4 \text{ k}\Omega$ ($R_n = 1 \Omega/sq$)
- Tbath = 150mK 250mK



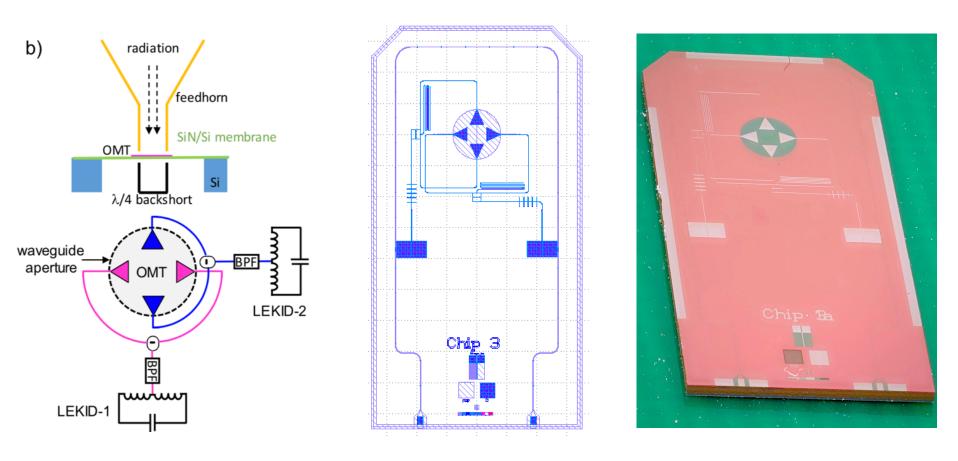
• P_{opt} = 5pW, Q_{i,opt} ~ 20k -40k, Q ~ 10k -20k





OMT-coupled MKIDs





- OMT very mature from TES-based implementation
- Keep all mm-wave components on chip identical to TES version, only replace TES with MKIDs, to reduce development work
- Use low-TLS amorphous Si instead of SiN

Coming next year, stay tuned!

Conclusion



- Large format (1000s of pixels on 6-in wafer) feedhorn-coupled MKID arrays based on TiN and hybrid TiN/Al absorbers on SOI wafers developed at NIST are becoming mature in terms of sensitivity, optical performance, fabrication and readout.
- For **single-band** polarimeter/total power detection applications **above 120GHz**, MKIDs are the first choice, with much simpler fabrication, operation and lower cost than TES.
- For **multichroic** applications and **CMB-Pol** applications in 100GHz 300GHz, OMTcoupled MKIDs are the proper solution which we are actively working on.
- Lower Tc superconductor that Al is needed from CMB applications below 90GHz.

JCMT 850um MKID array

- Pixel development: both TiN version (BLAST, Toltec) and new TiN/Al version (~6 mo)
- Select the best of the two and start array development (~6 mo)

Fist "fully working" and the greatest MKID array of all time! Collaborations and guest researchers are very welcome.